Unit in mm

TOSHIBA THYRISTOR SILICON DIFFUSED TYPE

## SF1500GX22

HIGH POWER CONTROL APPLICATIONS

 $\left. \begin{array}{l} : \text{ $V_{DRM}$} \\ : \text{ $V_{RRM}$} \end{array} \right\} = 4000 \text{V}$ Repetitive Peak Off-State Voltage Repetitive Peak Reverse Voltage

 $: I_{T(AV)} = 1500A$ Average On-State Current

Turn-Off Time :  $t_0 = 400 \mu s$  (Max.)

Critical Rate of Rise of On-State Current :  $di/dt = 250A/\mu s$ 

Critical Rate of Rise of Off-State Voltage: dv/dt=1500V/µs

Flat Package

## **MAXIMUM RATINGS**

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CHARACTERISTIC	SYMBOL	RATING	UNIT	
Repetitive Peak Off-State Voltage and Repetitive Peak Reverse Voltage	${ m v_{DRM}} \ { m v_{RRM}}$	4000	V	
Non-Repetitive Peak Reverse Voltage (Non-Repetitive $< 5$ ms, $T_j = 0 \sim 125$ °C)	$v_{ m RSM}$	4400	V	
R.M.S On-State Current	I <sub>T</sub> (RMS)	2355	Α	
Average On-State Current	I <sub>T</sub> (AV)	1500	Α	
Peak One Cycle Surge On-State	Imaz s	30000 (50Hz)	A	
Current (Non-Repetitive)	ITSM	33000 (60Hz)		
I <sup>2</sup> t Limit Value	${f I^2 t}$	$4500 \times 10^{3}$	$A^2s$	
Critical Rate of Rise of On-State Current (Note)	di / dt	250	A/μs	
Peak Gate Power Dissipation	$P_{GM}$	30	W	
Average Gate Power Dissipation	P <sub>G</sub> (AV)	4	W	
Peak Forward Gate Current	$I_{GM}$	6	Α	
Peak Forward Gate Voltage	$v_{FGM}$	30	V	
Peak Reverse Gate Voltage	$v_{ m RGM}$	5	V	
Junction Temperature	$T_{j}$	-40~125	$^{\circ}\mathrm{C}$	
Storage Temperature Range	$ m T_{stg}$	-40~125	°C	
Mounting Force	_	39.2±3.9	kN	

2 - \$65.2 ± 0.2 DEPTH : 2.5 ± 0.4 Ø 120MAX 1-(1) **CATHODE** 1- (2) CATHODE (BLACK) **ANODE GATE (WHITE) JEDEC** 

13-120J2A

Weight: 1350g

**EIAJ** 

**TOSHIBA** 

Note : VD=1/2 Rated, Tj=120°C, Gate Supply (VG=15V, RG=8 $\Omega$ , tr $\leq 1\mu$ s)

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## **ELECTRICAL CHARACTERISTICS**

CHARACTERISTIC	SYMBOL	TEST CONDITION		MIN.	MAX.	UNIT
Repetitive Peak Off-State Current and Repetitive Peak Reverse Current	I <sub>DRM</sub> IRRM	$V_{ m DRM} = V_{ m RRM} = { m Rated}, \ T_{ m j} = 125 { m ^{\circ} C}$		_	120	mA
Peak On-State Voltage	$V_{ extbf{TM}}$	$I_{TM} = 5000A, T_j = 25^{\circ}C$			2.4	V
Gate Trigger Voltage	$V_{GT}$	$V_{\mathbf{D}} = 12V, \ \mathbf{R_L} = 6\Omega$	$T_j = -40^{\circ}C$ $T_j = 25^{\circ}C$		4.5 3.5	V
Gate Trigger Current	$I_{GT}$		$T_j = -40^{\circ}C$ $T_j = 25^{\circ}C$	_	600 400	mA
Gate Non-Trigger Voltage	$v_{\mathrm{GD}}$	$V_{ m D}$ =1/2 Rated, $T_{ m j}$ =125°C		0.2	_	V
Gate Non-Trigger Current	$I_{\mathrm{GD}}$			5	_	mA
Delay Time	$t_{ m d}$	$V_D$ =0.5 Rated, $T_j$ =25°C Gate Supply ( $V_G$ =15V, $R_G$ =8 $\Omega$ , $t_r$ $\leq$ 1 $\mu$ s)		_	5	$\mu$ s
Gate Turn-On Time	tgt			_	10	μs
Turn-Off Time	$t_{ m q}$	$I_{T}$ =1200A, $V_{R}$ \geq 200V, $dv/dt$ =25V/ $\mu$ s, $T_{j}$ =115°C, $V_{DRM}$ =1/2 Rated		_	400	μs
Holding Current	$I_{\mathrm{H}}$	$T_j = 25$ °C, $R_L = 6\Omega$		_	300	mA
Critical Rate of Rise of Off-State Voltage	dv/dt	V <sub>DRM</sub> =1/2 Rated, T <sub>j</sub> =125°C Gate Open Exponential Rise		1500	_	V/μs
Thermal Resistance	R <sub>th (j-f)</sub>	Junction to Fin		_	0.0125	°C/W











